

# Ladder Classification

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# Overview

- ❑ Goal: Classification of ladders based on number of good (bad) channels
- ❑ Using data from bench test
  - ❑ Combining data from N and S, making total number of bad channels for each ladder
- ❑ Based on the code developed by Cheng-Wei and Han-Sheng
- ❑ 82 ladders classified (out of 84 ladders at BNL)

# Methodology

# Criteria

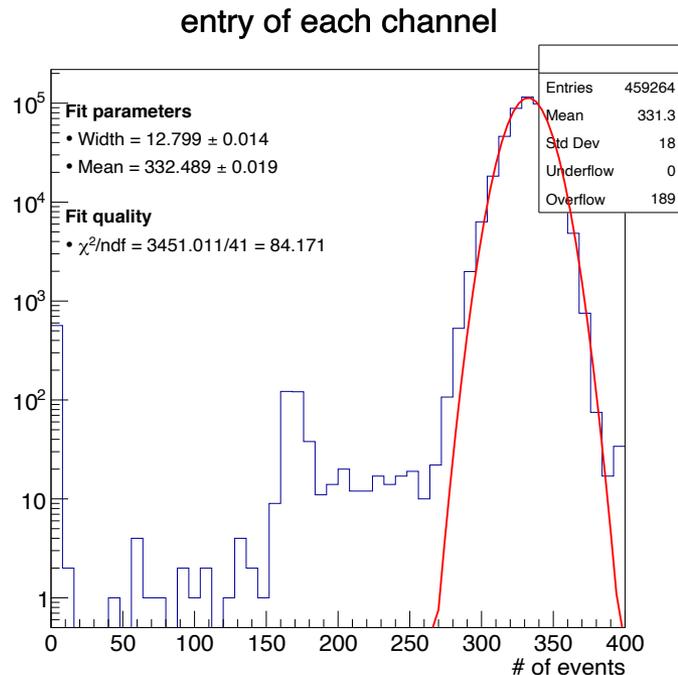
- ❑ Using the established scheme which consist out of 7 criteria:
  - 1) # of entries in each channel
    - To count the number of dead, hot and abnormal channels
  - 2) Width of amplitude distribution from all partial inclusive amplitude distribution
    - To quantify the overall noise at all comparators
  - 3) Threshold for each individual comparator
    - To check the threshold position of each individual comparator are correctly set.
  - 4) Width of amp distribution vs. comparator (linearity)
    - To quantify the variation of noise vs. comparator
  - 5) mean of amplitude of adc0
    - To check the offset of ADC response
  - 6) Linearity of amplitude mean vs. ADC
    - To check the linear response of amplitude mean vs. ADC
  - 7) Slope of amplitude mean vs. ADC
    - To check the gain of ADC. Note: can be corrected via calibration in principle

# 1) # of entries in each channel

**Purpose:** To quantify the overall noise at all comparators

## Method:

- Making 1-D histogram of the channel entry distribution from all channels of all ladders
- Fit with a Gaussian and define the boundary for good channels
- Good channels within 5-sigma of the Gaussian distribution



# 2) Width of amplitude distribution

**Purpose:** To quantify the overall noise at all comparators

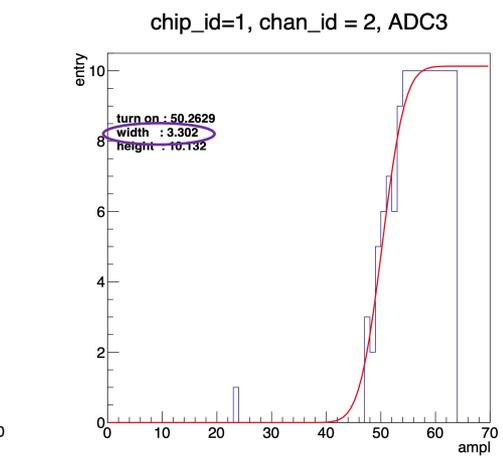
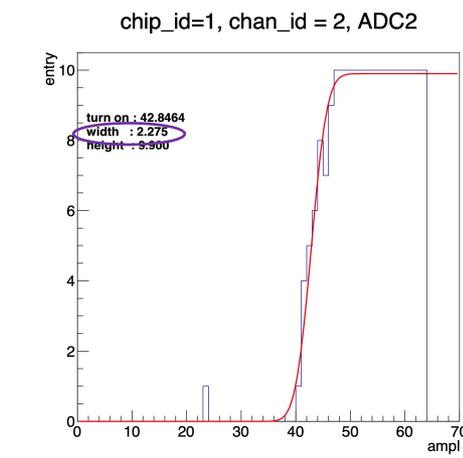
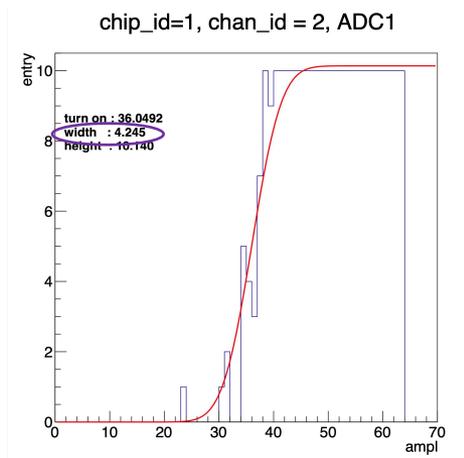
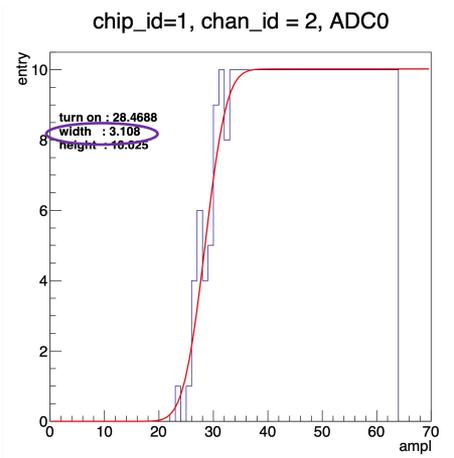
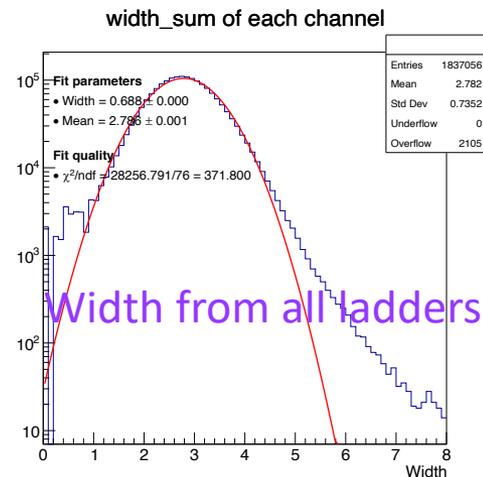
**Method:**

➤ Fit the following amplitude distributions with error function.

- ADC0 || ADC1 || ADC2.... || ADC7
- ADC1 || ADC2 || ... ADC7
- ...
- ADC7

➤ The mean and width correspond to the threshold and its noise at each comparator

➤ Good channels have width within 5-sigma of the all-ladders mean value

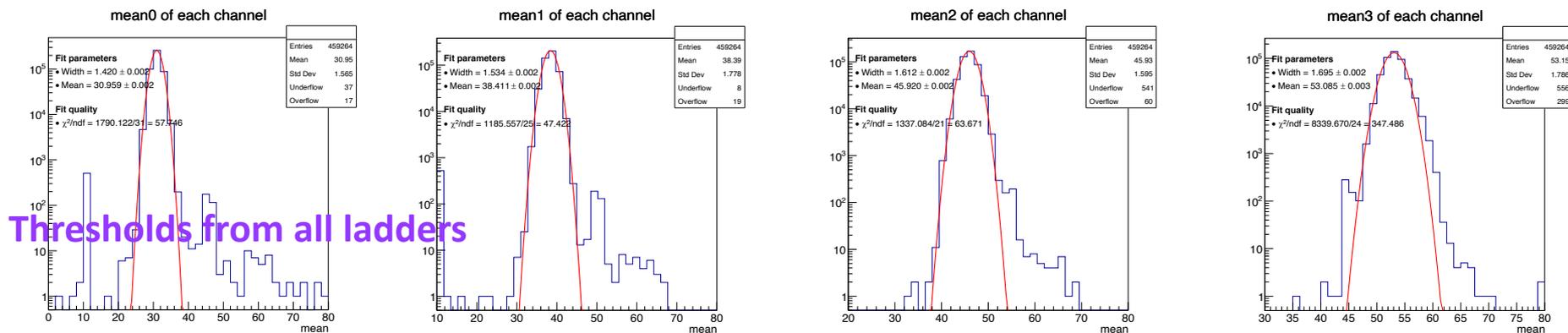


# 3) Threshold of each individual comparator

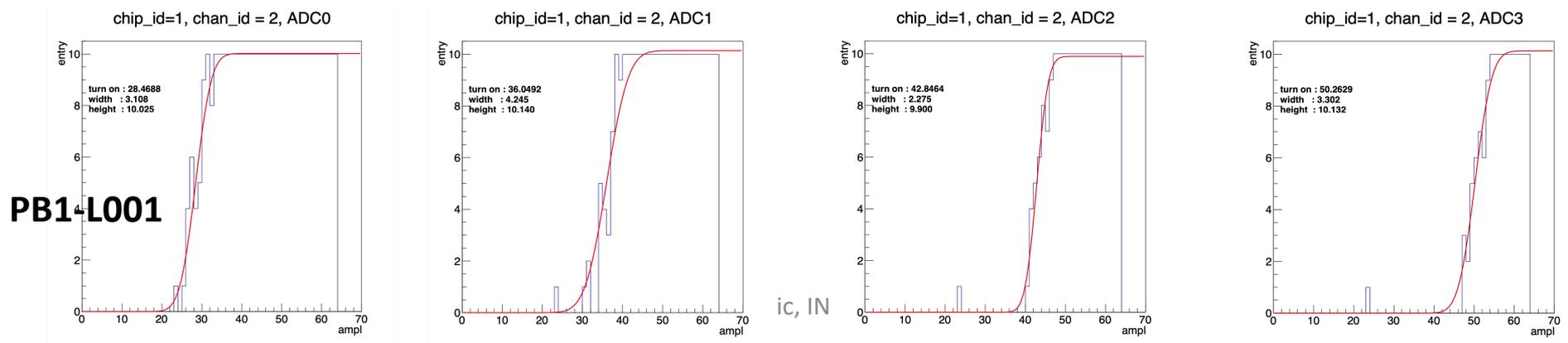
**Purpose:** To check the threshold position of each individual comparator are correctly set

**Method:**

- obtained threshold distribution via fitting partial inclusive amp distribution
  - Similar as on previous slide
- If any of the 4 threshold beyond boundary, this channel is bad
  - Boundary determined by all-ladders distribution threshold for each competitor



Thresholds from all ladders



# 4) Width of amp distribution vs. comparator

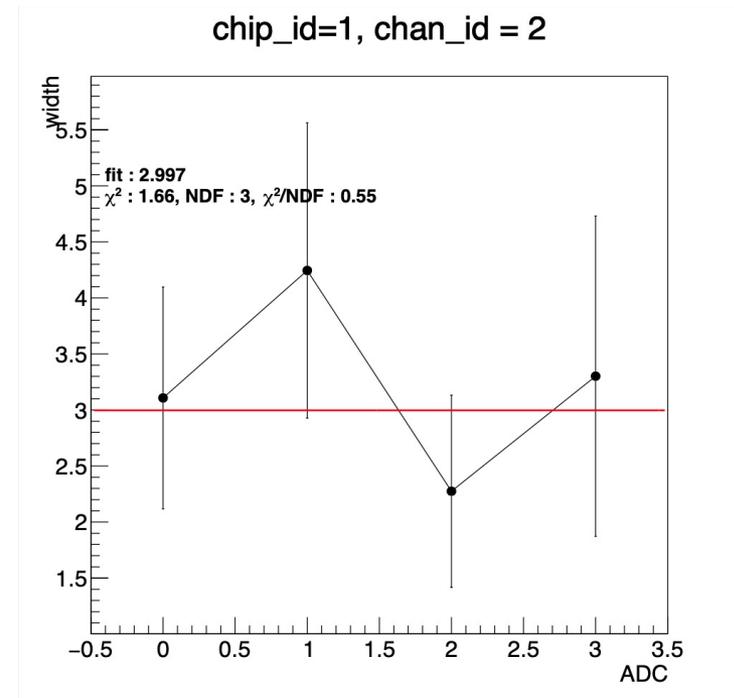
**Purpose:** To quantify the variation of noise vs. comparator

## Method:

- plot "width vs. comparator ID",
  - width is the error function width of the amplitude distribution.
- Chip is bad if the probability that the function is not constant is less than 0.0000006 (more than 5 sigma)

p value = (Chi2,NDF) = 0.65

**PB1-L001**



# 5) Mean of amplitude of adc0

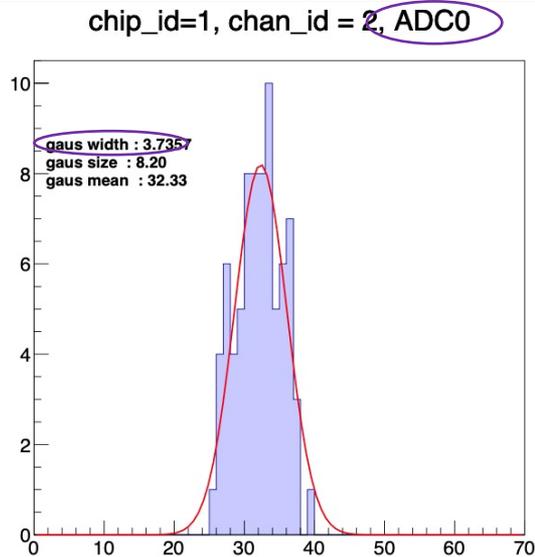
**Purpose:** To check the offset of ADC response

**Method:**

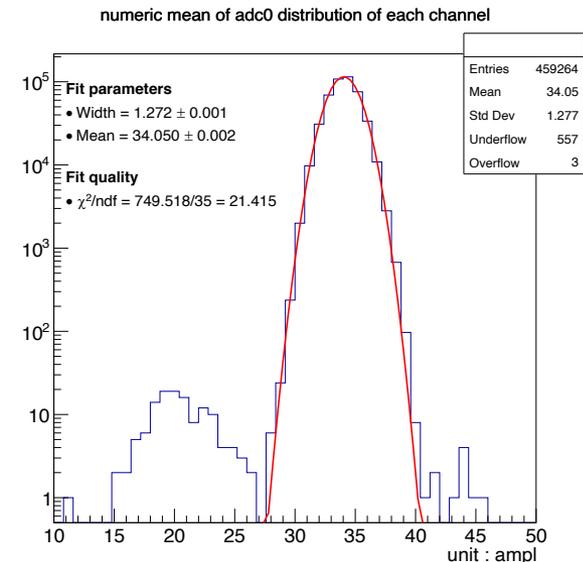
- Make a 1-D distribution of the amplitude mean of adc0 from all channels of all ladders.
- The channel is bad if fails more than 5 sigma away of the all-ladders average value

## PB1-L001

### Single channel ADC0 distribution



### Distributions of ADC0 means, from all ladders



# 6) Linearity of amplitude mean vs. ADC

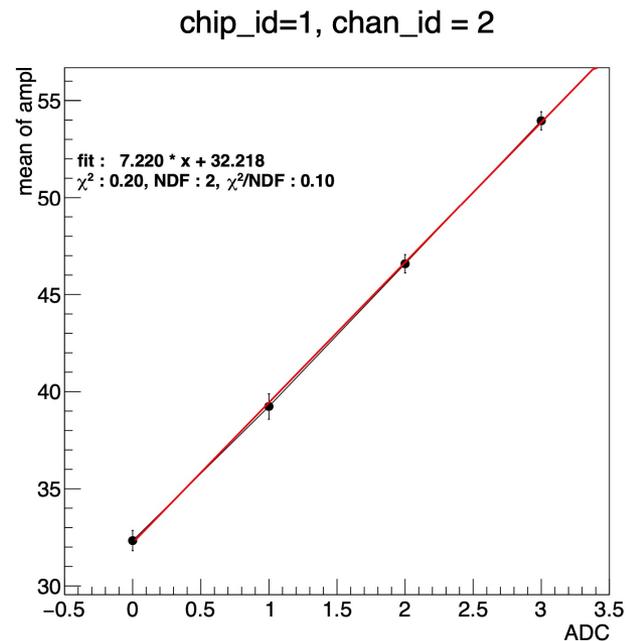
**Purpose:** To check the linear response of amplitude mean vs. ADC

## Method:

- plot "mean amplitude vs. ADC",
  - mean is the error function mean of the amplitude distribution.
- Chip is bad if the probability that the function is not linear is less than 0.0000006 (more than 5 sigma)

p value = (Chi2,NDF) = 0.9

**PB1-L001**



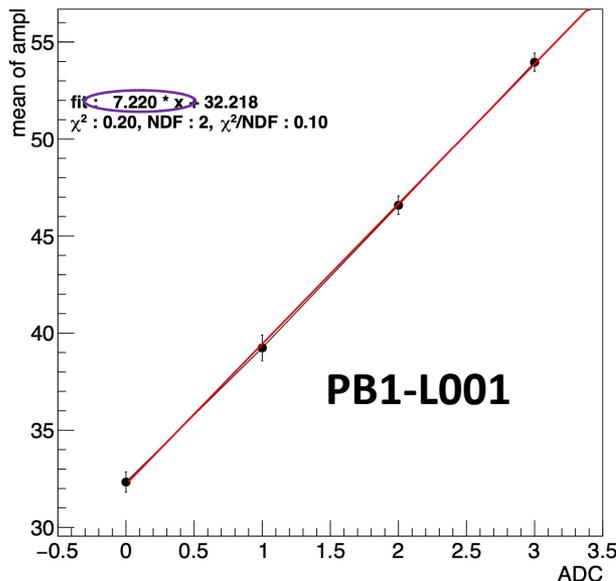
# 7) 7.Slope of amplitude mean vs. ADC

**Purpose:** To check the linear response of amplitude mean vs. ADC

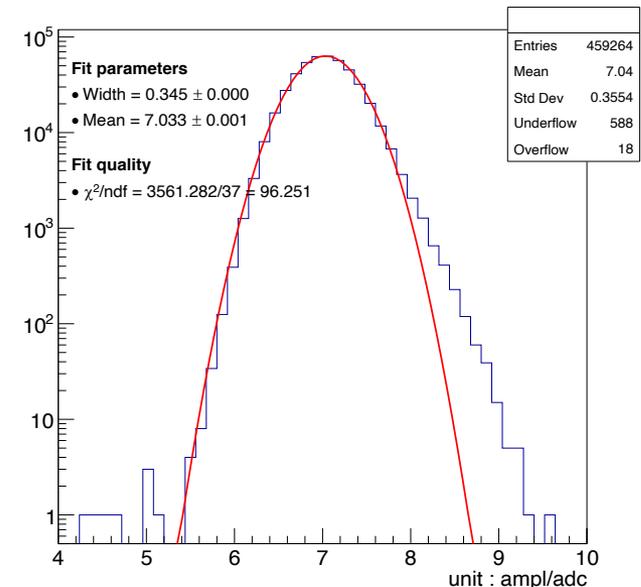
## Method:

- plot "mean amplitude vs. ADC",
  - mean is the error function mean of the amplitude distribution.
- Do the calibration of slope vs. chip ID
  - to remove the signal attenuation in different path length.
- The chip is bad if the slope is more than 5 sigma of all-ladders average value

chip\_id=1, chan\_id = 2



slope value of each channel after correction



# Results

# Classification table

- ❑ Totally analyzed 82 ladders
- ❑ Most of them are class 1 (<0.5% of bad chips)

Classification	Barrel 1 (24 needed)	Barrel 2 (32 needed)
Class 1 ( $\leq 0.5\%$ )	26	40
Class 2 ( $> 0.5\% \ \&\& \ \leq 1.0\%$ )	5	2
Class 3 ( $> 1.0\% \ \&\& \ \leq 2.0\%$ )	0	1
Class 4 ( $> 2.0\% \ \&\& \ \leq 3.0\%$ )	3	5

Details for each ladders: [link](#)

# Check with bench test

82		Total	South Chips/HDI Status													North Chips/HDI Status														
Count	New Name	Barrel Type HD / Stave Glued	Stave Batch-ID	U26	U25	U24	U23	U22	U21	U20	U19	U18	U17	U16	U15	U14	Data File	U26	U25	U24	U23	U22	U21	U20	U19	U18	U17	U16	U15	U14
				Hd ID	U13	U12	U11	U10	U9	U8	U7	U6	U5	U4	U3	U2	U1	Name	U13	U12	U11	U10	U9	U8	U7	U6	U5	U4	U3	U2
3	PB2_L003	2	Batch 1	2	2	2	2	2	2	2	2	2	2	2	2	2	20210329-1036_0,2	2	2	2	2	2	2	2	2	2	2	2	2	2
8	PB1_L003	1	Batch 1	2	2	2	2	2	2	2	2	2	2	2	2	2	20210325-1919_0,2	2	2	2	2	2	2	2	2	2	2	2	2	2

Ladder	Bench test	Classification
PB2-L003	One bad chip (U15)	138 bad channels (2.07%) Class 4
PB1-L003	Half entries issue (U7)	149 bad channels (2.2%) Class 4
PB1-L018	No issues spotted	39 bad channels (0.6%) Class 2

- ❑ Ladder classification algorithm can quantify issues observed during the bench test
- ❑ It can also detect unusual behavior of chips, that cannot be seen with bench test only







# Summary

Ladder classification based on bench test data

81 ladders classified

Final results once we have all ladders

# Backup

# Methodology table



Tests	Purpose	Method	Bit position of the Criteria
1.Number of channel entries	To count the number of dead, hot and abnormal channels	<ul style="list-style-type: none"> <li>1-D histogram of the channel entry distribution from all channels of all ladders</li> <li>Fit with a Gaussian and define the boundary for good channels.</li> <li>Good channels within around 5-sigma of the Gaussian distribution</li> </ul>	2 <sup>nd</sup> bit
2.Width of amp distribution from all partial inclusive amp distribution	To quantify the overall noise at all comparators.	<ul style="list-style-type: none"> <li>Obtain the threshold of each comparator (CR). Fit the following amp distribution with error function. The mean and width correspond to the threshold and noise at each comparator.                             <ul style="list-style-type: none"> <li>ADC0    ADC1    ADC2...   ADC7</li> <li>ADC1    ADC2    ... ADC7</li> <li>ADC2    ADC3    ... ADC7</li> <li>ADC3    ADC4    ... ADC7</li> <li>ADC4    ADC5    ... ADC7</li> <li>ADC5    ADC6    ADC7</li> <li>ADC6    ADC7</li> <li>ADC7</li> </ul> </li> <li>Combine all width into a single width distribution.</li> <li>Good channels within around 5-sigma of the Gaussian distribution</li> </ul>	10 <sup>th</sup> bit
3.Threshold of each individual comparator.	To check the threshold position of each individual comparator are correctly set.	<ul style="list-style-type: none"> <li>obtained threshold distribution via fitting partial inclusive amp distribution.                             <ul style="list-style-type: none"> <li>In calibration we can see 4 ADC values, i.e., 4 threshold can be checked.</li> </ul> </li> <li>Set criteria for each threshold and reject outliers.                             <ul style="list-style-type: none"> <li>If any of the 4 <u>threshold</u> beyond boundary, this channel is bad.</li> </ul> </li> </ul>	1 <sup>st</sup> bit
4.Width of amp distribution vs. comparator	To quantify the variation of noise vs. comparator.	<ul style="list-style-type: none"> <li>plot "width vs. comparator ID", where width is the error function width of the amplitude distribution.</li> <li>fit the plot with a constant line, i.e. "pol0" in ROOT, and obtain chi2/NDF from the ROOT.</li> <li>Calculate p-Value, i.e. <u>TMath::Prob</u>(chi, NDF)</li> <li>Set cut based on the distribution.                             <ul style="list-style-type: none"> <li>e.g.                                     <ul style="list-style-type: none"> <li>p-Value = 0.006%--&gt; 5 sigma</li> </ul> </li> </ul> </li> </ul>	11 <sup>th</sup> bit

5.Linearity of amplitude mean vs. ADC	To check the linear response of <u>amplitude</u> mean vs. ADC	<ul style="list-style-type: none"> <li>plot "mean of the amplitude vs. ADC", where the mean is the Gaussian mean of the amplitude distribution.</li> <li>fit the plot with a straight line, i.e. "pol1" in ROOT, and obtained chi2/NDF from the ROOT.</li> <li>Calculate p-Value, i.e. <u>TMath::Prob</u>(chi, NDF)</li> <li>Set cut based on the distribution.                             <ul style="list-style-type: none"> <li>e.g.                                     <ul style="list-style-type: none"> <li>p-Value = 0.006%--&gt; 5 sigma</li> </ul> </li> </ul> </li> </ul>	5 <sup>th</sup> bit
6. mean of amplitude of adc0.	To check the offset of ADC response.	<ul style="list-style-type: none"> <li>Make a distribution of the amplitude mean of adc0 from all channels of all ladders.</li> <li>5-sigma as boundary.</li> </ul>	4 <sup>th</sup> bit
7.Slope of (amplitude mean vs. ADC)	To check the gain of ADC. Note: can be corrected via calibration in principle	<ul style="list-style-type: none"> <li>first do the calibration of slope vs. chip ID                             <ul style="list-style-type: none"> <li>to remove the signal attenuation in different path length.</li> </ul> </li> <li>plot the distribution of the (slope of amp mean vs ADC) from all channels of all ladders.</li> <li>set boundary accordingly                             <ul style="list-style-type: none"> <li>5-sigma</li> </ul> </li> </ul>	9 <sup>th</sup> bit
8.Unbounded channel	Source test		To be added
<b>Classification</b>	To classify a ladder	<ul style="list-style-type: none"> <li>remove double counting on bad channels from all above criteria</li> <li>plot "number of single ladders" vs. "number of bad channels"</li> <li>printout the ladder information for each class.</li> </ul>	classification based on the percentage of bad channels in a full ladder <ul style="list-style-type: none"> <li>1: 1.0%</li> <li>2: 2.0%</li> <li>3: 3.0%</li> <li>4: 4.0%</li> </ul>